





13th International "Hiroshima" Symposium on the Development and Application of Semiconductor Tracking Detectors (HSTD13)



Time resolution of single pixel irradiated 3D devices up to $10^{17} n_{eq}/cm^2$ at 120 GeV SPS pion beams

<u>Evangelos – Leonidas Gkougkousis</u>

University of Zurich, CERN

•3D Sensors

Timing at Extreme Fluences

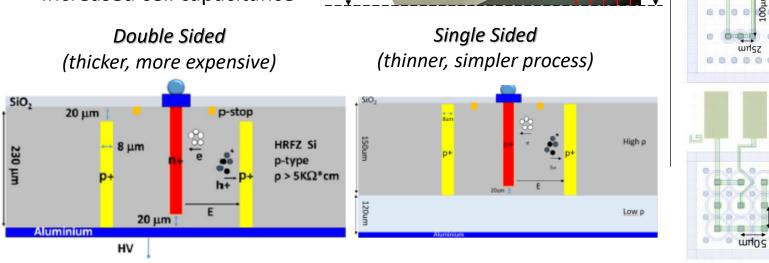
3D Sensors: Decoupling of charge generation and drift volume (*Standard columns, TimeSpot, Hex geometries* ect.)

Pros

- High radiation tolerance up to several times 10¹⁶ n_{eq}/cm²
- Short drift distances with fast rise times
- Reduced Landau fluctuation, practically non-existent for perpendicular tracks

Cons

- Non-uniform field geometry
- Lower production yield
- Increased cell capacitance



8.2 mm





Double Active High R ✓ Pixe ✓ Cap ✓ 10 ✓ Clo ATLCS Sing Acti

0 0 0 0 0 0

0 0 0 0

Double sided n-on-p process Centre Nacional de Microelectrònica Active thickness 190 μ m (total thickness 230 μ m) High Resistivity (> 2 k Ω m × cm) Fz silicon

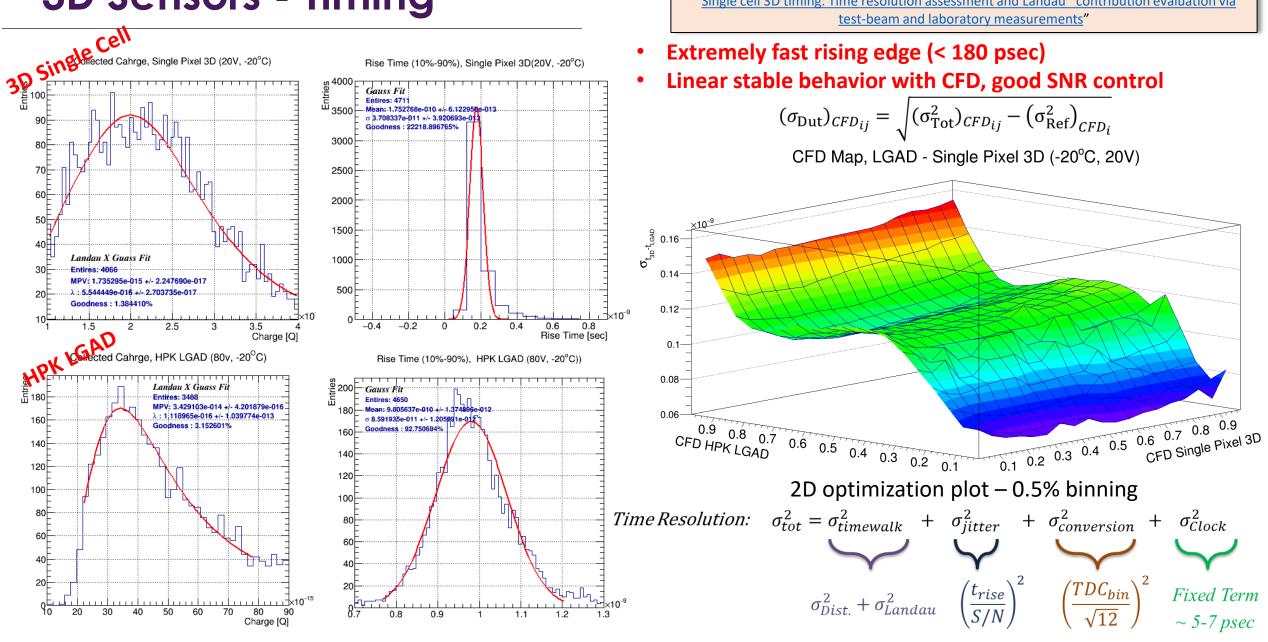
- \checkmark Pixel Size 55 × 55 μ m²
- ✓ Capacitance ~80 pF
- 🖌 10 μm column diameter
- ✓ Closest electrode distance: 19 µm

ATLES Pre-Production type

Single sided n-on-p process Active thickness 130 μ m (total thickness 150 μ m) High Resistivity (> 2 k Ω m × cm) Fz silicon

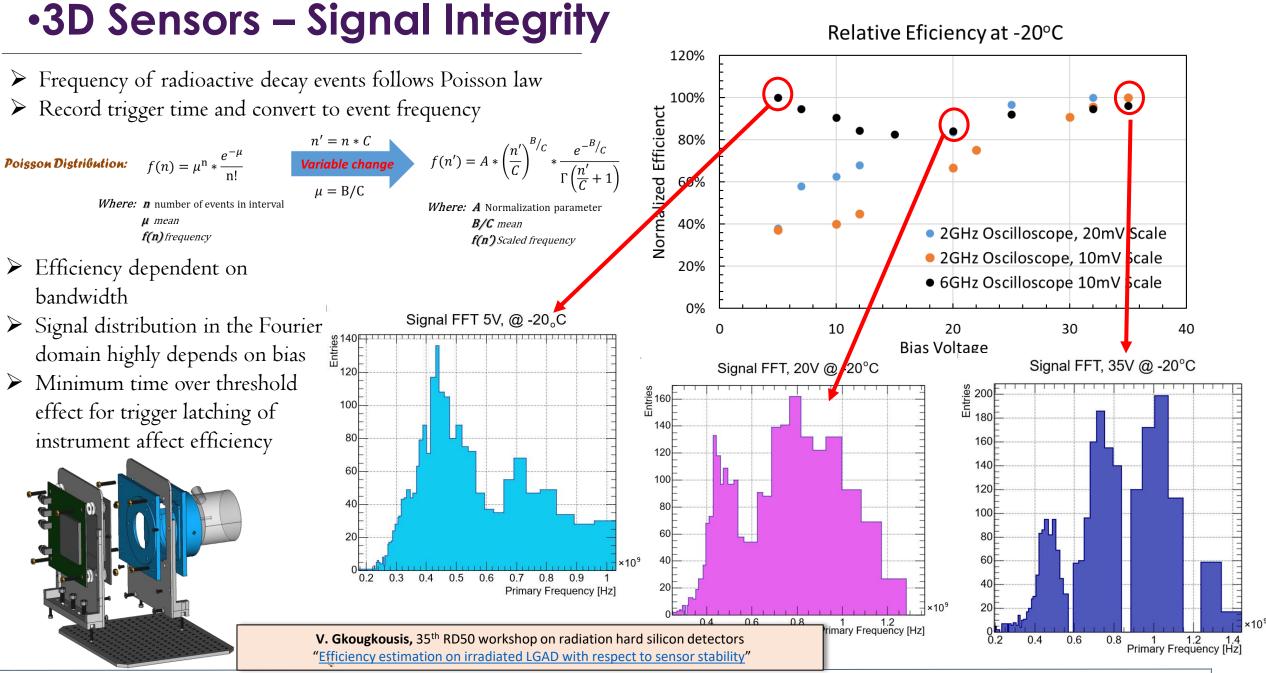
- $\checkmark~$ Pixel Size 25 \times 100 μm^2
- ✓ Capacitance ~ 20 pF
- ✓ 8 µm column diameter
- ✓ Closest electrode distance: 35.5 µm
- ✓ Pixel Size $50 \times 50 \ \mu m^2$
- ✓ Capacitance ~ 37 pF
- 🗸 8 µm column diameter
- ✓ Closest electrode distance: 19.3 µm

•3D Sensors - Timing



V. Gkougkousis, 17th Trento workshop on advanced radiation silicon detectors "Single cell 3D timing: Time resolution assessment and Landau contribution evaluation via

E. L. Gkougkousis



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Planar Sensors

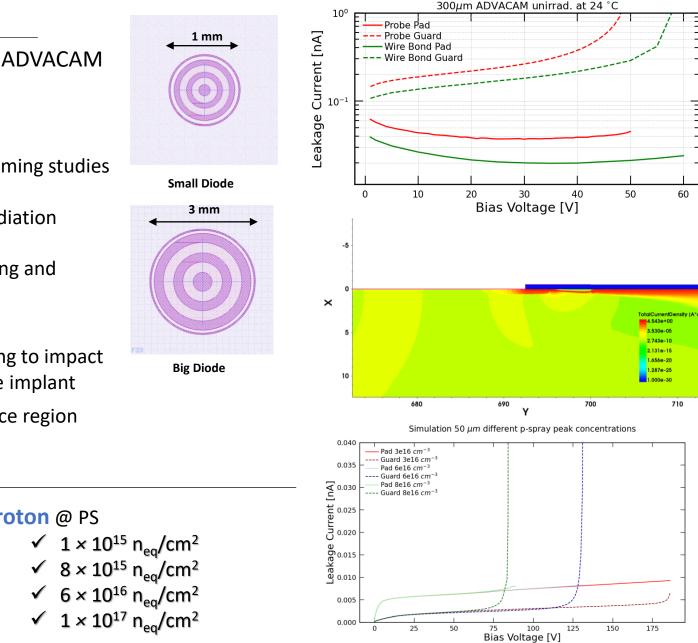
Sensors: CERN EP-R&D n-on-p planar sensor run with ADVACAM at 50, 100, 200 and 300 µm active thickness

Test Structures

- Small diodes (3.14 mm2 active area) Circular diodes for timing studies due to lower capacitance
- Big diodes (28.27 mm2 active area) Circular diodes for radiation damage studies
- 5x5 Pixel matrix (0.003 mm2 active area) for charge sharing and interpixel efficiency – timing studies

Issues

- Early breakdown due to high p-spray concentration leading to impact ionisation at the interface between p-spray and electrode implant
- Breakdown first visible in guard ring due to bigger interface region compared to pad



(both 3D and planar)

Irradiations

Neutron @ JSI (Ljubljana)

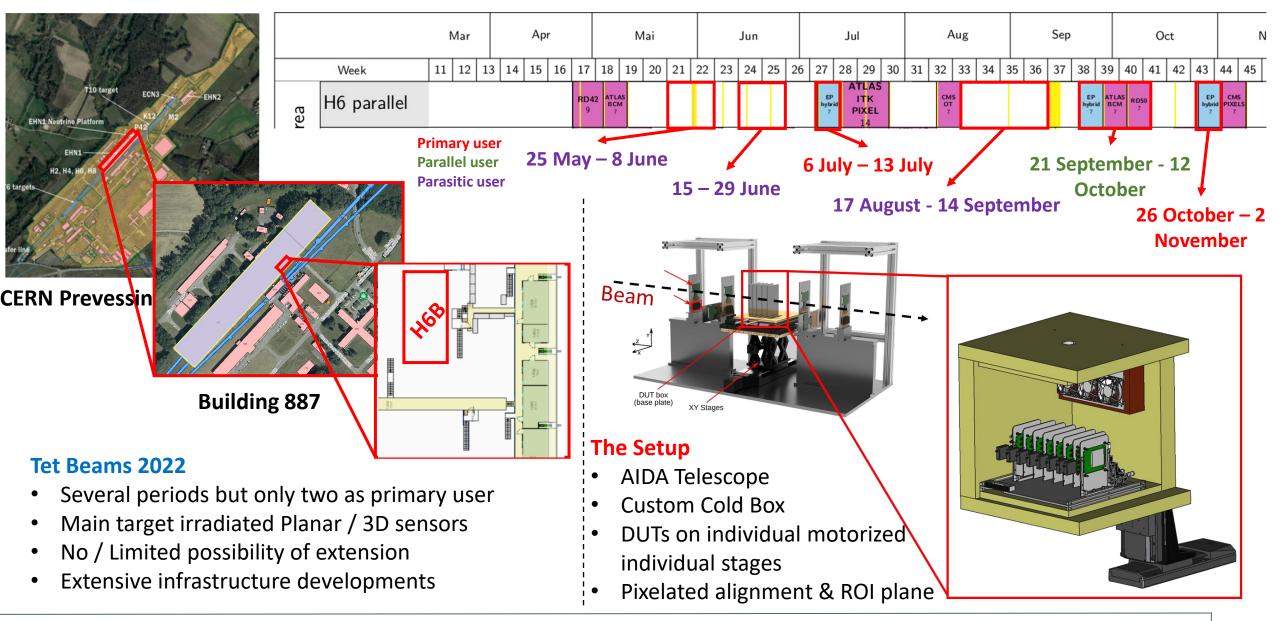
 \checkmark 1 × 10¹⁵ n_{eq}/cm² ✓ $8 \times 10^{15} n_{eq}^{-7}/cm^{2}$ ✓ $6 \times 10^{16} n_{eq}/cm^2$ $\checkmark 1 \times 10^{17} \, n_{eo}^{-1}/cm^{2}$

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Proton @ PS

•Part I - Test Beams

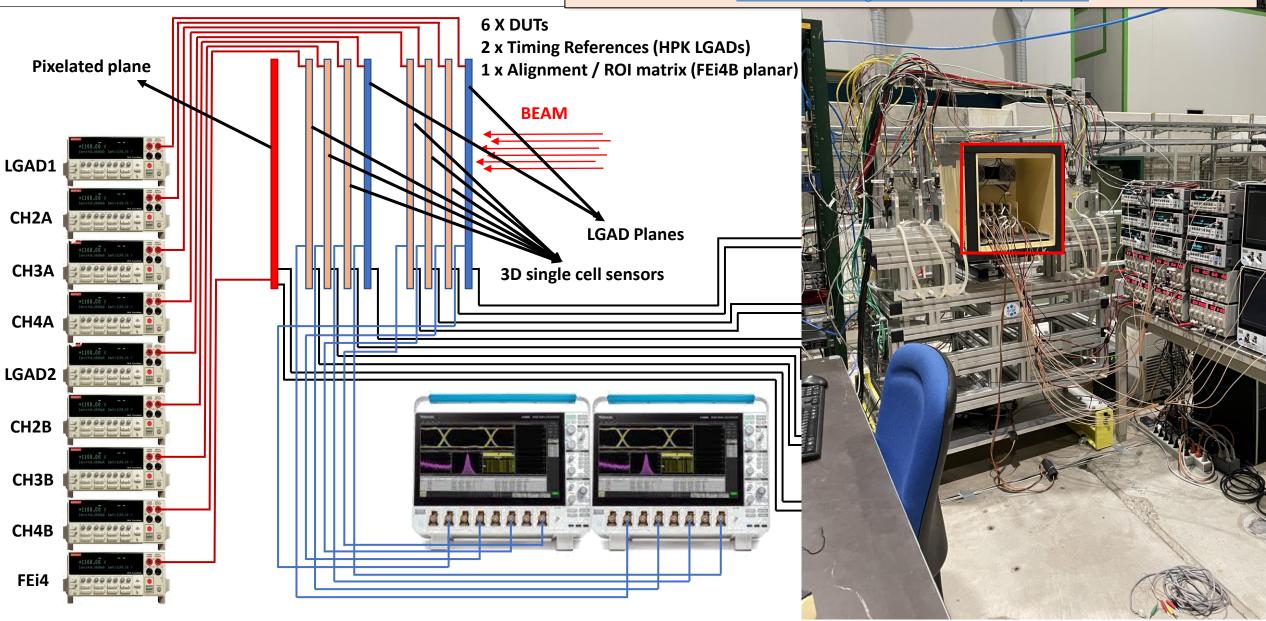




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Test Beam Configuration

V. Gkougkousis, 40th RD50 Workshop on Radiation hard semiconductor devices for very high luminosity colliders "Time resolution of single cell 3D devices on SPS pion beams"



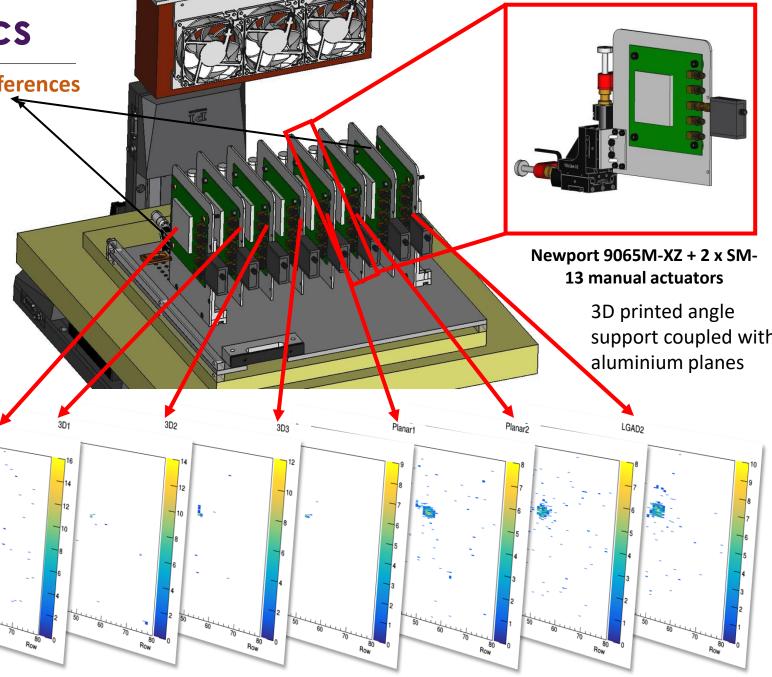
Alignment & Mechanics

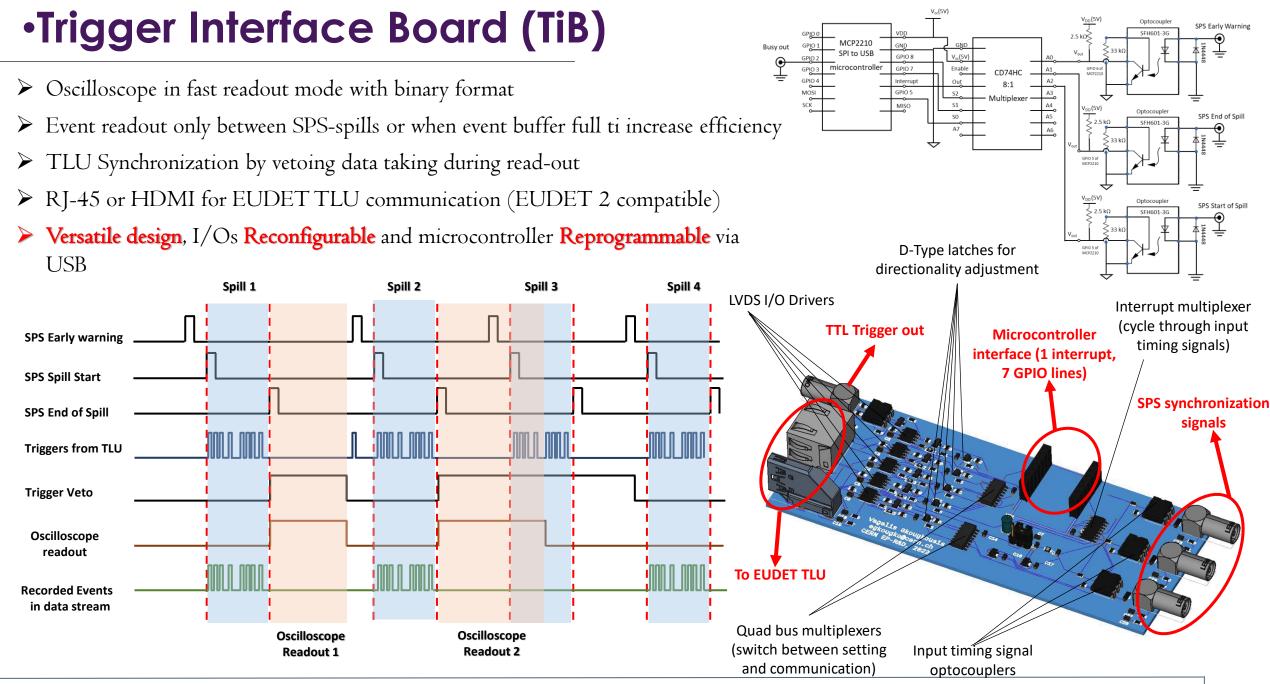
HPK LGAD Timing references

LGAD1

- Coincidences between DUTs and LGADs required for timing
- > Alignment crucial to increase data efficiency
- Efficiency defined by largest overlapping region
- Micrometric on-line alignment using projections on FEi4 matrix
- ROI defined in addition to other trigger conditions



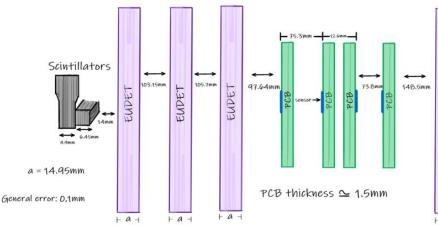




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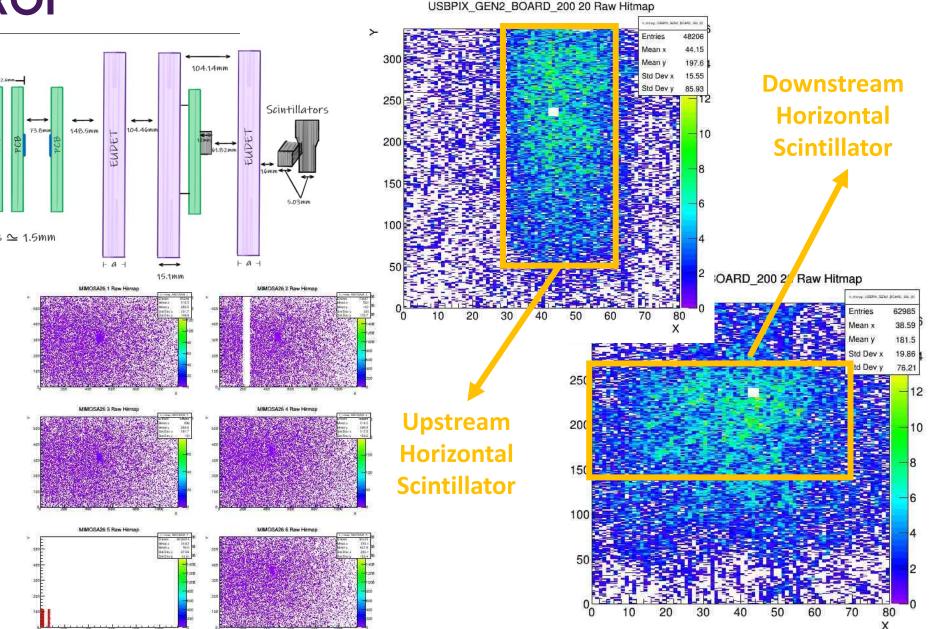
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Telescope Planes

- 6 MIMOSA planes for tracking
- Plane no. 5 known to be bad
- 5 μm 7 μm tracking resolution
- Estimated acquired number of events ~1M
- Limited beam control as parasitic user
- Suffer from low intensity and low data rates of EUDAQ

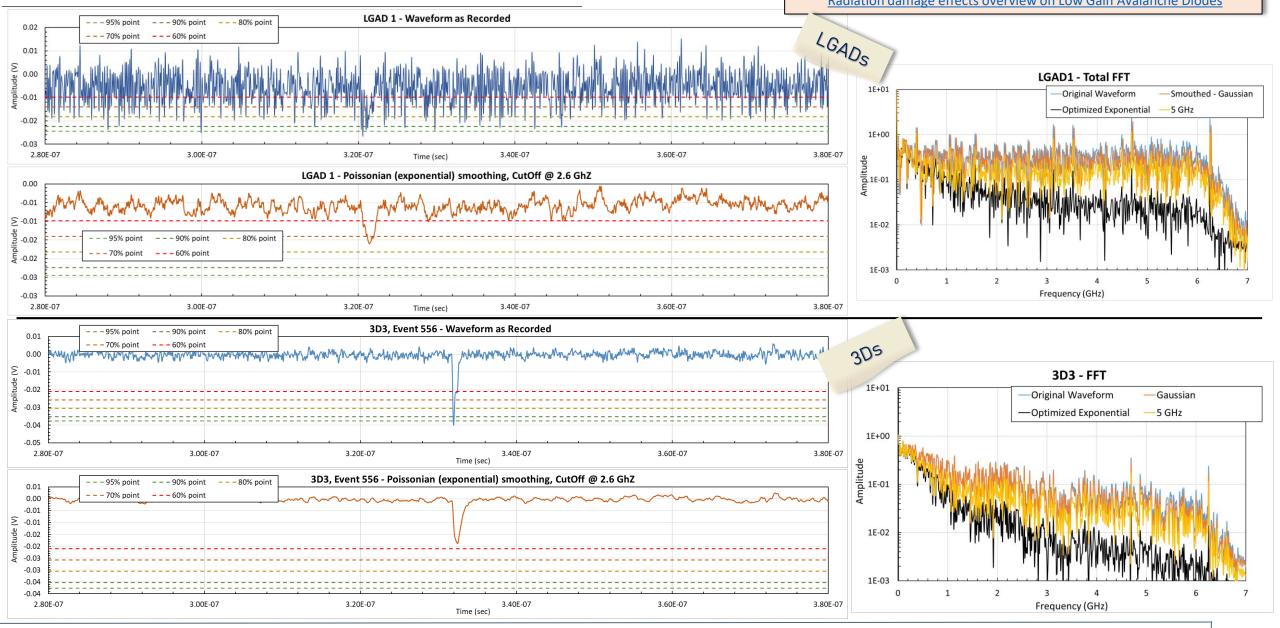


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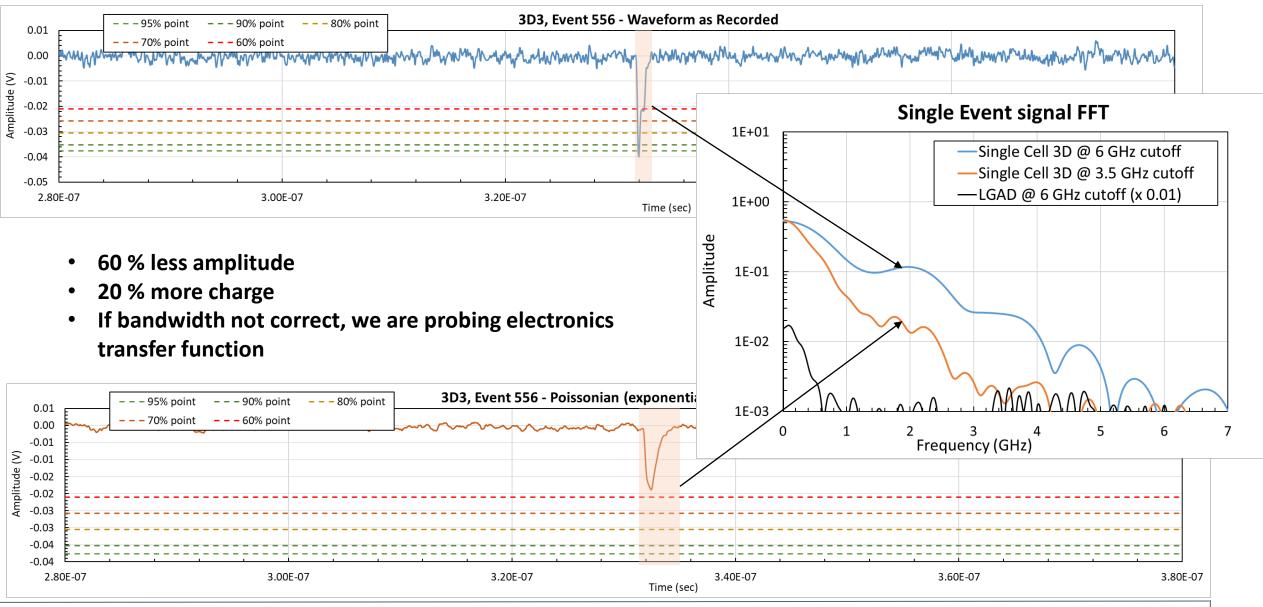
The importance of bandwidth

V. Gkougkousis, Ultrafast imaging and tracking Instrumentation, Methods and Applications Conference - ULITIMA 2023 "Radiation damage effects overview on Low Gain Avalanche Diodes"



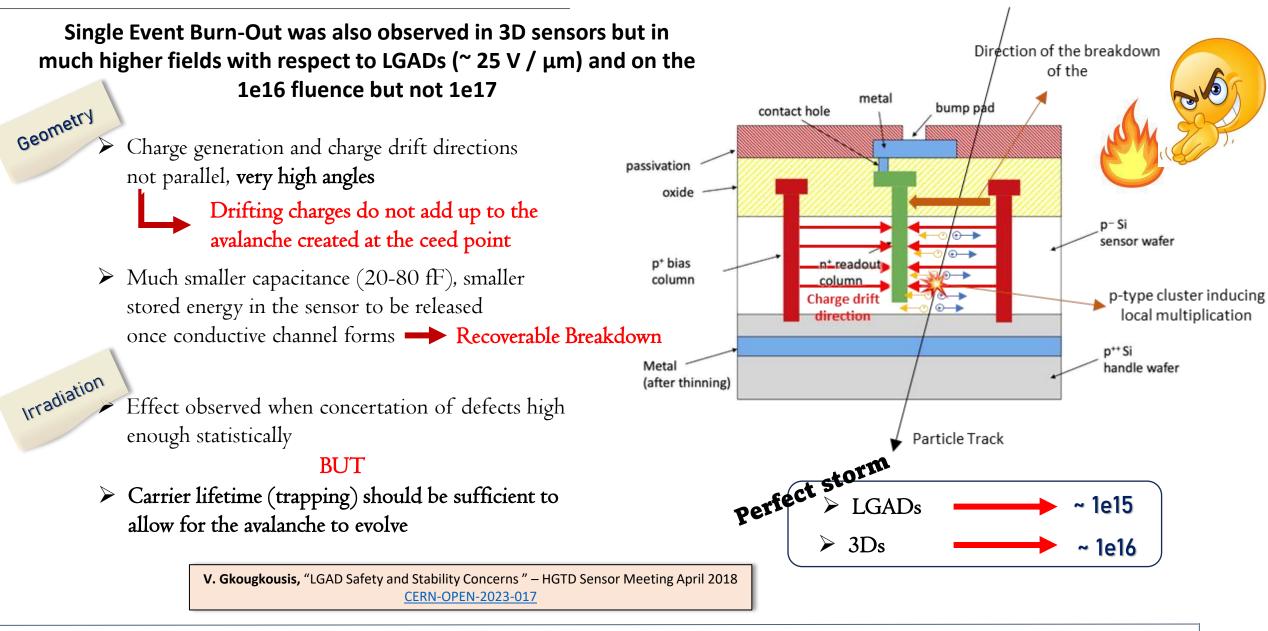
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The importance of bandwidth

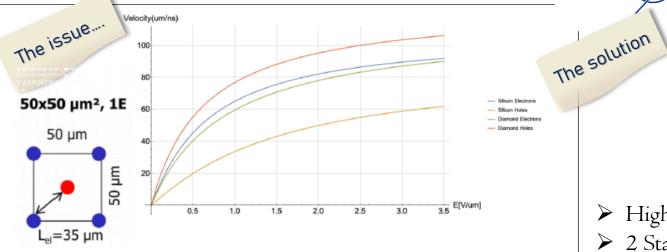




•Single Event Burn-out



•16 Channel Board



- Assuming a linear filed dependence and a -15 V operation point at 35 μ m column distance: $|E| \cong 0.43 V/\mu m$
- Estimating drift velocity for electrons:

$$v_{drift}^{e} = \frac{\mu_{0,e} \times E}{\left[1 + \left(\frac{\mu_{0,e} \times E}{v_{sat.}^{e}}\right)^{\beta_{e}}\right]^{1/\beta_{e}}}$$

with $v_{sat.}^{e} = 107 \ \mu m/ns$, $\mu_{0,e} = 1417 \frac{cm^{2}}{v_{s}}$, $\beta_{e} = 1.109$

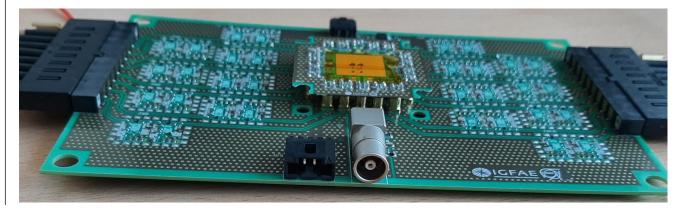
$v_{drift}^e \approx 41.4 \, \mu m/ns$

• Extrapolated Rise time and Frequency:

$$t_{Rise} \approx \frac{1}{3} \times t_s = \frac{1}{3} \times \frac{d/2}{v_{drift}^e} \approx 140 \ psec \Rightarrow 2.3 \ \text{GHz}$$

July 2021 October 2021 April 2022 June 2023 Timeline
Design submission Initial tests 2nd Mezzanine Test beam measurement
iteration with planar matrix

- High frequency multichannel versatile board
- * Mezzanine design for fast sensor interchangeability
- Suitable for matrices (AC-LGAD applications) but also for single pad devices
- ➢ High Frequency SiGe discreate electronics @ 12 GHz bandwidth
- \blacktriangleright 2 Stage configuration with a transimpedance followed by a voltage stage
- $\blacktriangleright\,$ Low max current (~10mA) with well behaved gain linearity vs V_{DD}
- Ruggers 3000 High Frequency substrate
- Pre-assembled miniaturized coaxial edge connectors with panelmounted SMA plugs (Im cable length)
- \blacktriangleright 140 x140 mm outer dimensions

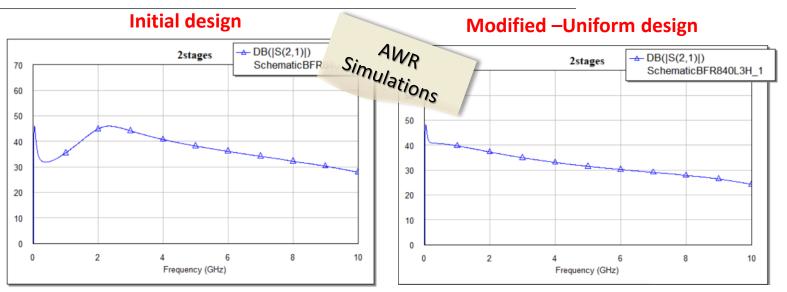


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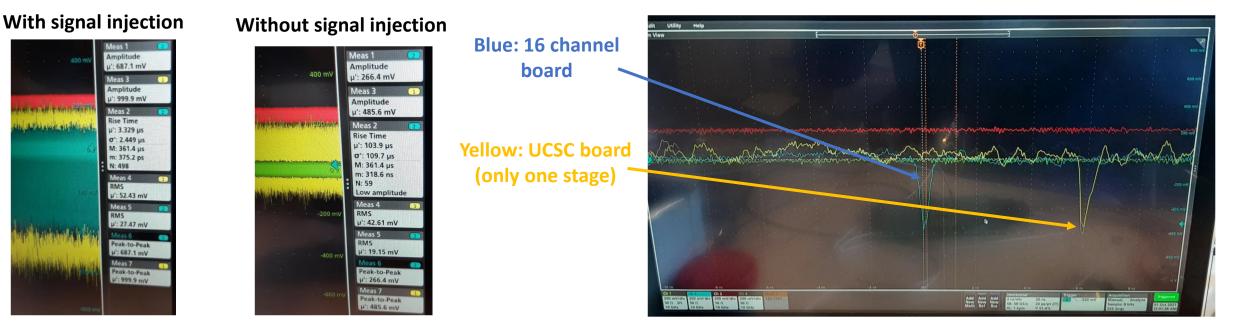
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GFAE

Simulations and performance I

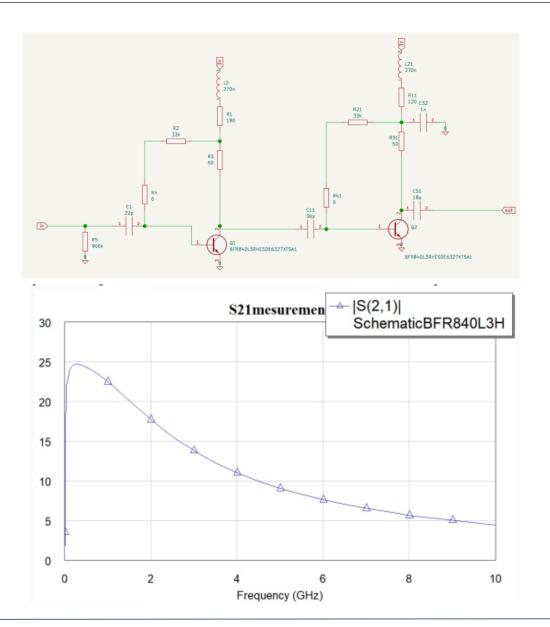


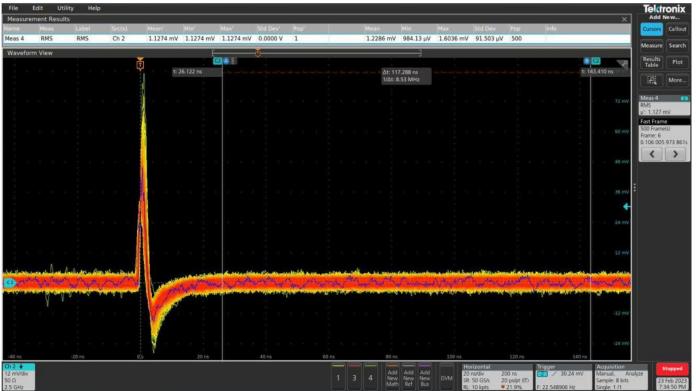
- Optimized design for uniform response with frequency
- No sharp gain change discontinuities
- No undershoot/overshoot observed
- ➢ Gain moderated to ∼70 for a two-stage configuration
- 20% Higher SNR than UCSC board (with both stages)
- 2 x SNR with respect to UCSC board + niniCircuits second stage amplifier
- On going energy and transimpedance simulation



Simulations and performance II

Edgar Lemos Cid, 18th Trento Workshop on Advanced Silicon Radiation Detectors "Multichannel board for picosecond timing measurements of silicon sensors"





- > Mean noise (~RMS) of 1.2 mV for a gain of ~ 70
- \blacktriangleright Tested with a 55 x 55 μ m 3D double sided sensor of 230 μ m
- Not frequency optimized for this sensor geometry with fast dropout at lower scale
- Leads to bipolar signal due to the increased trans-impedance at lower frequencies

Conclusions

3D Pixels - Planar measurement campaign

- Several productions under investigation of different pixel size and thickness
- Estimate filed non-uniformity impact on time resolution vs pixel size
- Determine minimal acceptable thickness for time resolution applications (SNR)
- Investigate effects after irradiation up to 1e17 n_{eq}/cm² in protons and neutrons

Test-Beam Setup

- **Trigger Interface board:** Versatile, allows interfacing any acquisition instrument with EUDET
- Control Software: Polymorphic UI with seeming-less multi-instrument support
- **Cooling:** XPS cold box with web interface temperature controllable system @ -18°C
- Mechanics: Micrometric alignment with individual DUT stages
- **Analysis Framework:** Advanced framework with signal shapes, iterative re-fitting and shape-based noise rejection

Primary Goals

Special Thanks to all the students who participated

2022 Test beam Periods



Jakob Haimberger (CERN, TU Wien)



Oscar Ferrer (CNM Barcelona)



Hanae Tilquin (Imperial College London)



Efren Rodriguez (IGFAE)

2021 Test beam Periods



Efren Rodriguez (IGFAE)



Marius Halvorsen (CERN, Oslo University)



George Petrogiannis (IFAE Barcelona)



Pablo Fernández (IFAE Barcelona)

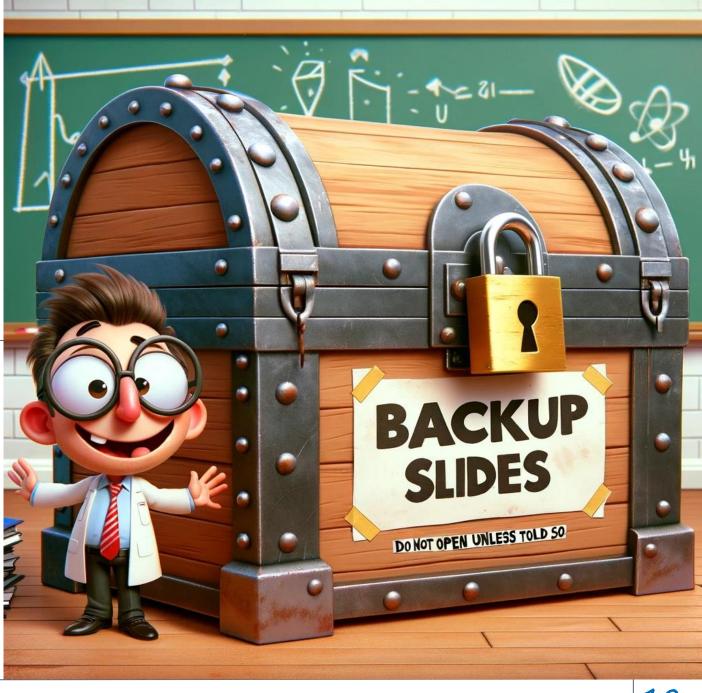


Eloi Pazos Rial (CERN)



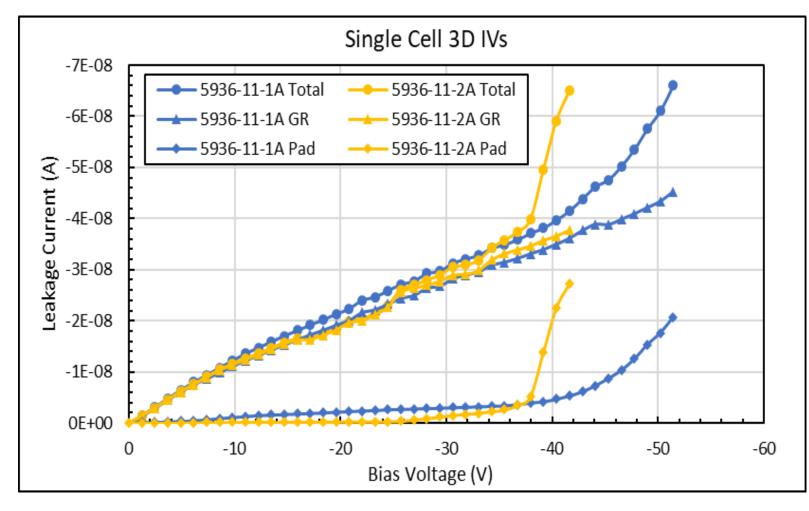
Alexandros Athanasios Kapelios (CERN, Uni Glasgow)

Backup



Introduction

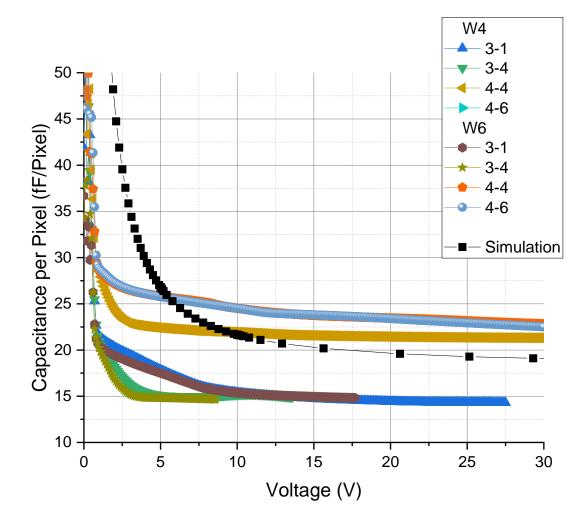
Test Geometry



- **Compliance:** 60 uA
- **MAX Volt:** 60V
- Voltage Step: 1V
- Setting time: 2 sec
- Averaging: 5 measurements
- **Temperature:** 20°C

Introduction

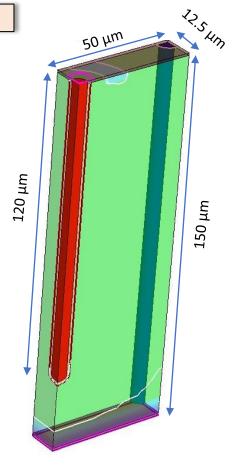
Capacitacne



Oscar Ferrer, CNM Barcelona

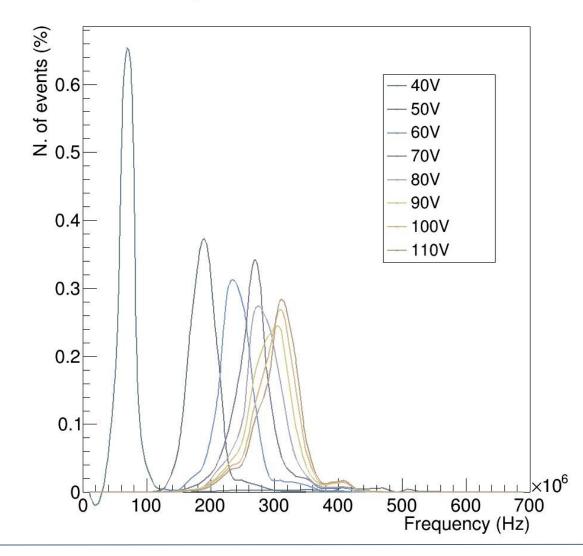
Simulated pixel:

- Single-Sided
- 150µm active thickness
- 120µm deep n+ columns
- Column diameter: 8µm
- P-stop radius: 12.5μm
- ¼ column simulated → applied mirror symmetry (computational time savings)



Signal Evolution with bias in LGADs

Signal FFT - 1e14n, -30C



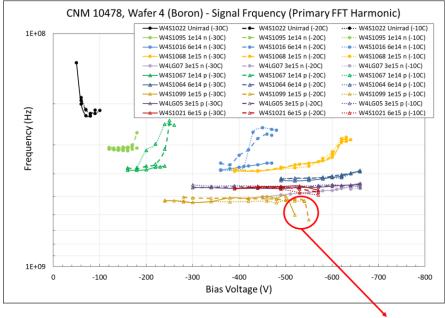
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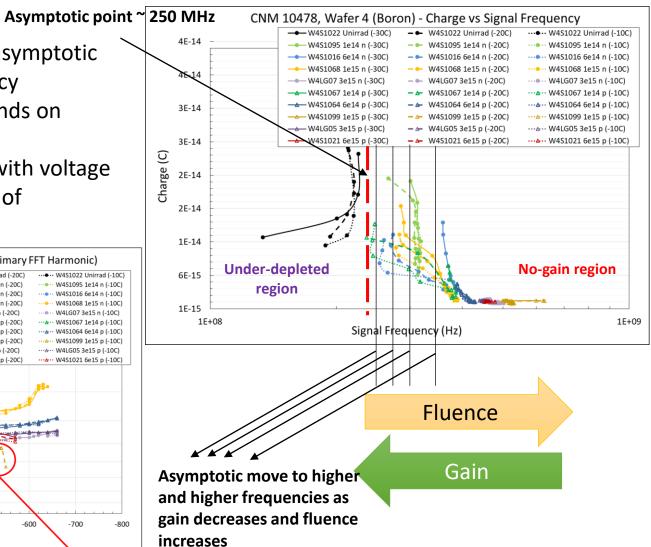
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Signal Analysis LGADs

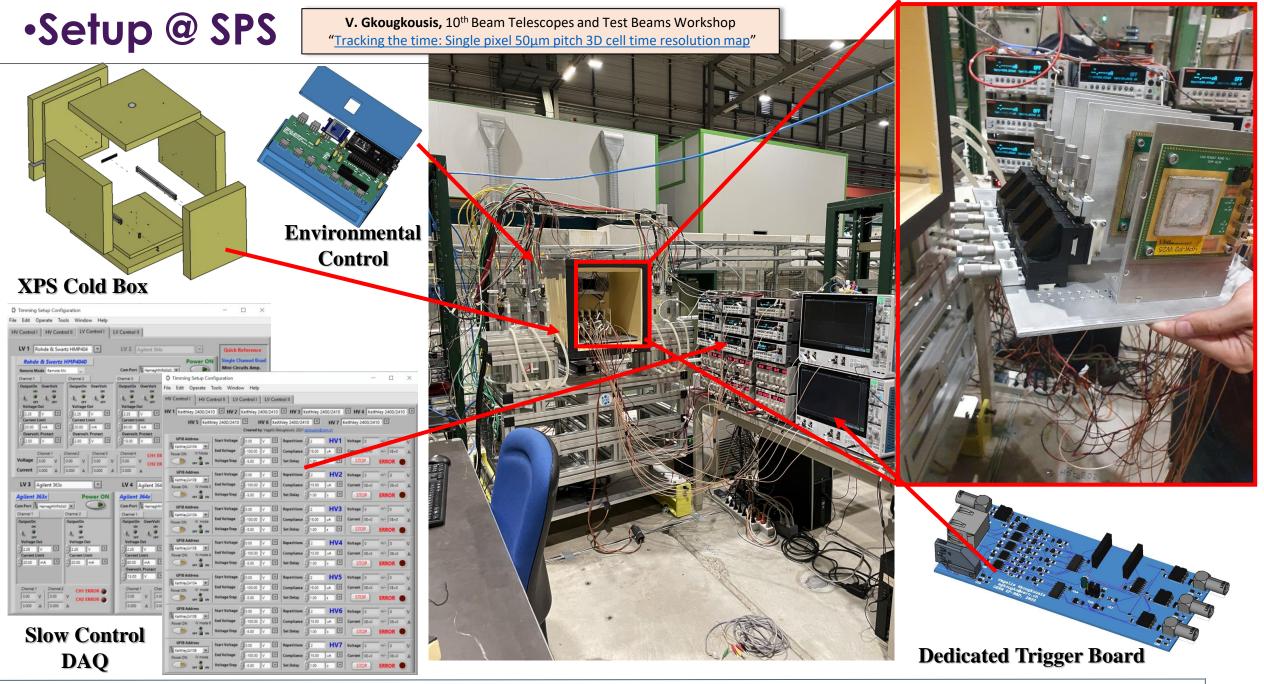
FFT

- ✓ FFT vs Voltage presents an asymptotic behavior towards a frequency
- ✓ Asymptotic frequency depends on fluence and remaining gain
- Signal frequency increases with voltage and decreases on the onset of multiplication





High Frequency noise, sensor in breakdown



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•HV & LV Control/monitoring

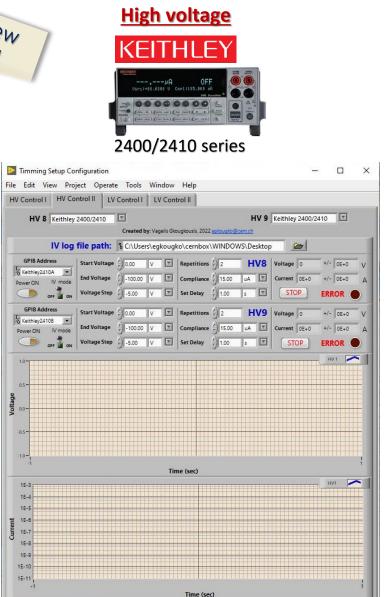
Timming Setup Configuration Edit View Project Operate To		
V Control I HV Control II LV Cont	Control II	
LV 1 TTi-PL303	LV 2 Agilent 364x 💌 Quick	Reference
TTi PL303 Powe	Agilent 364x Power ON Single (hannel Bo
Com Port % GPIB0:7:INSTR •	Com Port HamegHMP4040 - 1st sta	ge amplifie
Channel 1 Channel 2		nce -> 17n tage -> 2.2
OutputOn OverVolt OutputOn Over	OutputOn OverVolt OutputOn OverVolt Overvolt	t prt> 2.5
1	1 9 1 9 1 9 1 9 Transim	er Gan ~10 p.: 470 Ohn
OFF OFF OFF Voltage Out Voltage Out	OFF OFF OFF OFF	Bandwidth
()2.25 V T ()2.25 V		ircuits Amp
Current Limit Current Limit Current Limit Current Limit Current Limit		nce -> 50n tage -> 12\
Overvolt. Protect Overvolt. Prote	Overvolt. Protect Overvolt. Protect Overvolt	t prt> 13\
		Bandwidth
Channel 1 Channel 2 CH1 ERRO	Channel 1 Channel 2 March 4 March 10	ince -> 75m
0.00 V 0.00 V CH2 ERRO	0.00 V 0.00 V CH3 EPROP Low Vol	tage -> 5.0
0.000 A 0.000 A	Overvor	t prt> 5.5 r Gian ~ 10
LV 3 Rohde & Swartz HMP404	LV 4 Anilent 364x	FEi4
Konde & Swartz HiviP404	4 LV P	SU channel
Rohde & Swartz HMP4040	Power ON - VDA ->	
Remote Mode Remote Mix 🗸	- VDD ->	iance: 700 n • 1.3 V
Channel 1 Channel 2 OutputOn OverVolt OutputOn Over		ance 500 m
ON ON ON	ON ON ON ON COmpli	iance: 200 n Conv> 25
CIEF OFF OFF	OFF OFF OFF OFF Compli	iance: 200 n
Voltage Out Voltage Out	Voltage Out Voltage Out	EnviE
Current Limit Current Limit	Current Limit - 5 V US	B power fro
1 1 <td>Vervolt, Protect Overvolt, Protect Complia</td> <td></td>	Vervolt, Protect Overvolt, Protect Complia	
2.50 V T 2.50 V	1300 V T 1300 V T Low Vol	ince ->200n Itage ->5V
	Jar	t prt> 5.50
Voltage 0.00 v 0.00 v 0.00	Channel 4 CH1 ERROR CH3 ERROR	ad here Man and
Current 0,000 A 0,000 A 0,0	CH2 ERROR CH4 ERROR Gkoug	ed by: Vagelis gkousis, 2022
Current 0.000 A 0.000 A 0.	0.000 A eakou	ako@cern.ch

Multi-model Support with Polymorphic UI



Timming Setup Cor	nfiguration			Labviev based	
le Edit View Proj		w Help		LUVIEL	
HV Control I HV Co	ntrol II LV Control I LV Co	ontrol II		Dasad	
IV 1 Keithley 2400/241	0 HV 2 Keithley 2400/241	0 🔄 HV 3 Keithley 2400/2	2410 🗵 HV 4 Keithl	ey 2400/2410	
HV 5 Keith	And a second	eithley 2400/2410 🔽 H Gkougkousis: 2022 egkougko@cem.ch	IV 7 Keithley 2400/2410		
GPIB Address	Start Voltage			+/- OE+0 V	
Keithley2410A	End Voltage () -100.00 V			+/- OE+0 A	
Power ON IV Mode	Voltage Step () -5.00 V			ERROR	
GPIB Address	Start Voltage	Repetitions () 2			
Keithley2410B	End Voltage ()-100.00 V			+/- 0E+0 V +/- 0E+0 A	
Power ON IV mode 2	Voltage Step			+/- OE+0 A	
OFF ON					
GPIB Address	Start Voltage		HV3 Voltage 0	*/- 0E+0 V	
Power ON IV mode	End Voltage () -100.00 V			+/- OE+0 A	
	Voltage Step	Set Delay 7 1.00 s	T STOP I	ERROR	
GPIB Address	Start Voltage	Repetitions	HV4 Voltage 0	+/- 0E+0 V	
Power ON IV mode 4	End Voltage		Current OE+0	+/- 0E+0 A	
OFF OF ON	Voltage Step 分 -5.00 V	Set Delay	STOP	ERROR	
GPIB Address	Start Voltage	Repetitions / 2	HV5 Voltage 0	+/- 0E+0 V	
Keithley2410A Power ON IV mode	End Voltage ()-100.00 V	Compliance / 15.00 UA	Current OE+0	+/- OE+0 A	
	Voltage Step	Set Delay	STOP		
GPIB Address	Start Voltage	Repetitions () 2	-IV6 Voltage 0	+/- 0E+0 V	
Keithley24108	End Voltage ()-100.00 V	Compliance	Current OE+0	+/- 0E+0 A	
	Voltage Step	Set Delay	STOP I		
GPIB Address	Start Voltage	Repetitions () 2	-IV7 Voltage 0	+/- 0E+0 V	
Keithley24108	End Voltage			+/- OE+0 A	
	Voltage Step				
		1 . A. A.			
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!• Constant monito-					
ring & logging					
ring & logging					
Live protection					

Precompiled executable available on GitLab: <u>here</u>



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Temperature Regulation

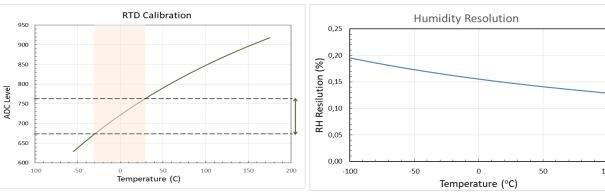
➢ Running at a crisp -18 ℃

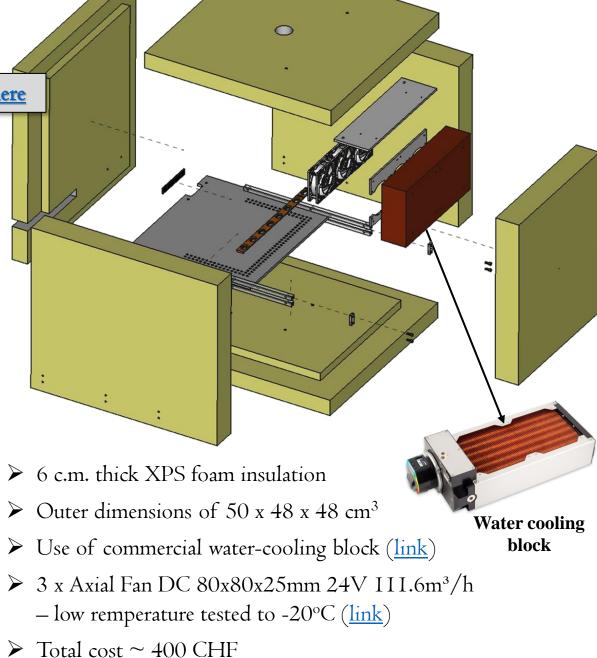
> EnviE GitLab with schematics: <u>here</u>

- ➢ Glycol cooling with temperature feedback Labview control
- \blacktriangleright Humidity regulation though N₂ feeds

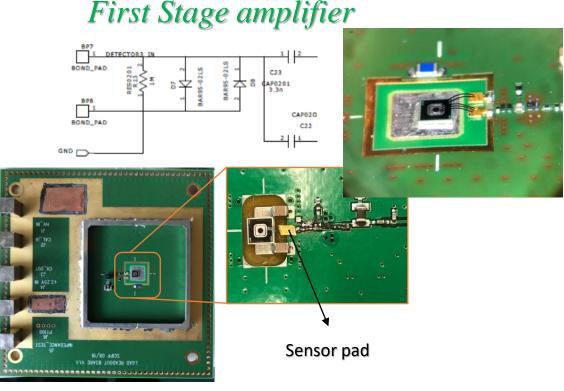
Environmental Expander V2.0 (EnviE)

- ESP8266 based with integrated 10-bit ADC, I2C and WiFi 802.11b
- Integrated OLED 128X64 pixel screen
- High precision voltage dividers and sensor decoupling
- ARDUINO / LoUA core web interface
- Temperature resolution of 0.8 °C \pm 0.06 %
- Humidity resolution 0.1 % with temperature compensation



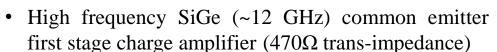


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Second Stage amplifier

- Mini-circuits (Gali 52+) Gallium arsenate voltage amplifier with a 2 GHz bandwidth for LGADs
- Mini-circuits (ZX60-V63+) 6 GHz microwave voltage amplifier for 3D and planar planes
- Amplification factor of ~ 10 at 12 and 5 V respectively
- Amplifiers mounted directly on the boards and placed inside the cold box



- Fully enclosed faraday cage surrounding sensor
- Mean sensor + amplifier noise < 1.8 mV
- Use of identical sensors for calibration and comparison

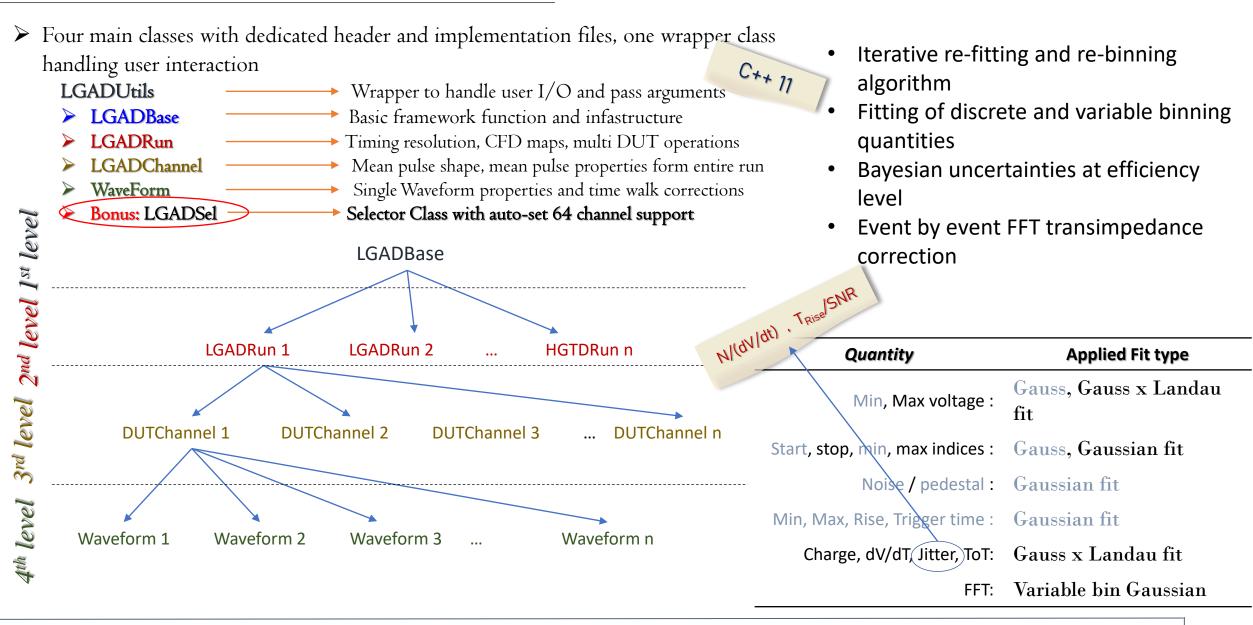


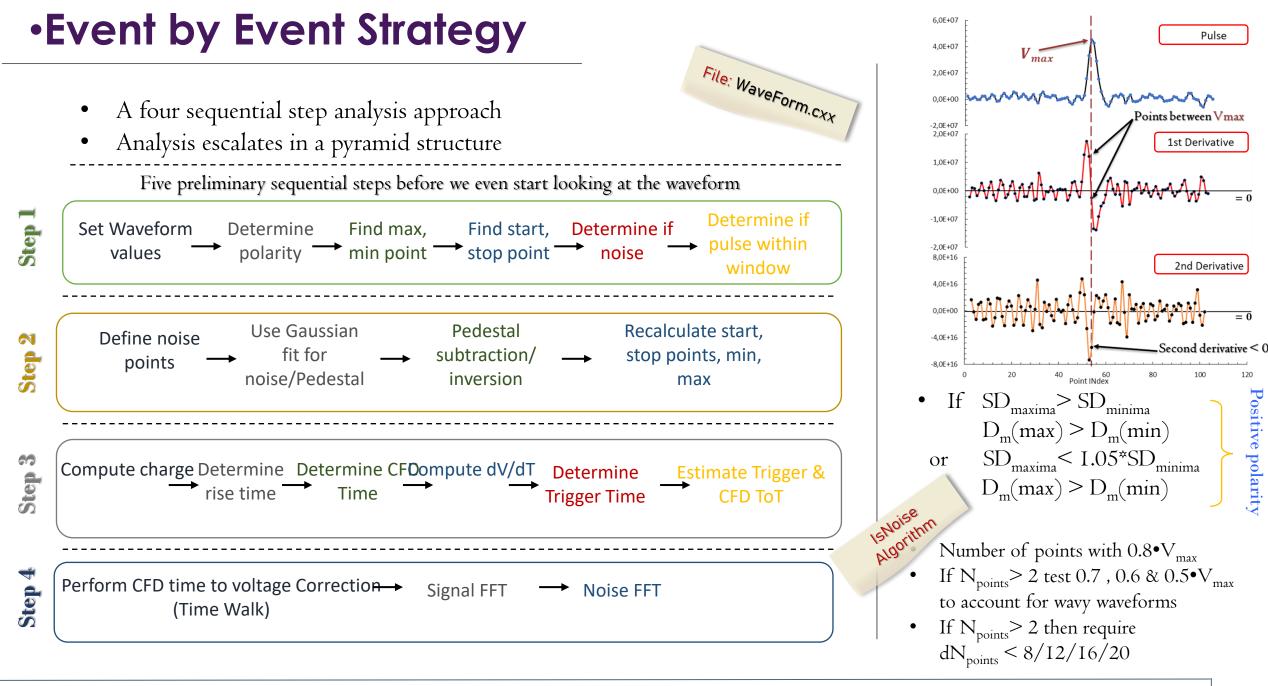
Gali 52+ GaAs , <2Ghz, 50Ω



ZX60-V63+ **50 - 6000 MHz, 50Ω**

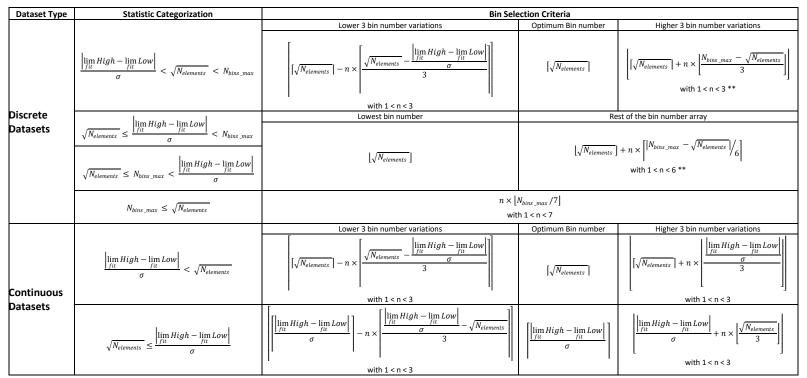
Analysis Framework





Iterative Re-fitter & signal templates

- Centralized fitter engine for all fits
- ➢ Fully automated, including limits, method and Minuit minimization
- ➢ 36 Iterations per fit with limits and bin size variation to determine best combination
- Vover-binning protection, automatic variable discreetness test
- Variable binning for FFT, frequency histograms
- Supported ROOFit, Standalone Minuit, Integral optimization or Shape



Template Method

Point by Point projection of all timewalk corrected (though CFD) signal pulses

File: LGADFits.cxx

- Landau X Gauss fit on projected point by point distribution
- Extraction of a "characteristic" signal composed of the MPVs of the Point by point projection fits
- RooKeyPdf for analytical description of signal
- Re-iteration on all events and fit of each waveform with the extrapolated analytical signal description
- Re-caclculate all quantities

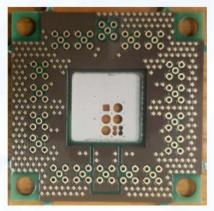
Sensor Daughterboard

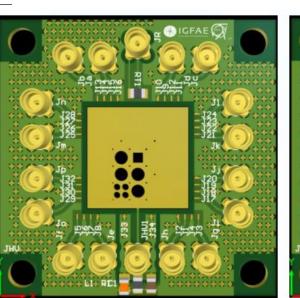
Edgar Lemos Cid, 18th Trento Workshop on Advanced Silicon Radiation Detectors "Multichannel board for picosecond timing measurements of silicon sensors"

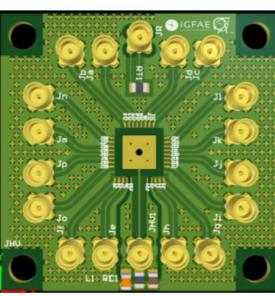
Sensor board

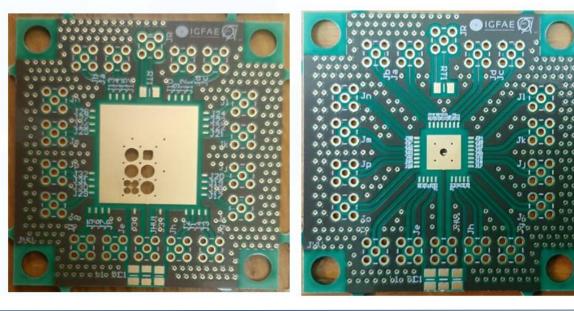
- Two types of designs. (15x15 mm and 5x5 mm central pad).
- 41 x 41 mm square shape.
- Rogers 4350B for the high speed signals.
- Connector area reinforce with 0.3 µm FR4.
- Under sensor pad thickness of 100 μm.
- Multiple drills design on the central pad to place different types and sensors sizes.
- 140 boards produced at <u>Gacem</u>.

Back side









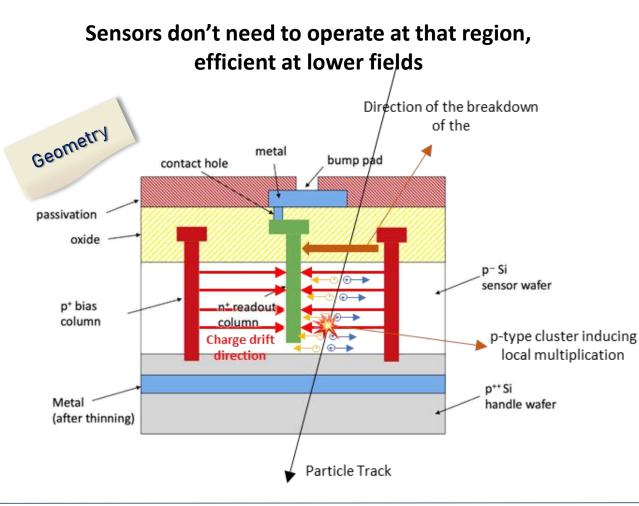
H/W and S/W developed

Category	Function	Description	Github Project Link
Electronics	TiB Board	Interface and synchronize oscilloscope with AIDA TLU	<u>Trigger Interface Board</u> <u>- TiB</u>
	FEi4 HitOr Converter	Convert CMOS level output to TTL level necessary for ROI trigger	HitOr Converter
	Environmental Expander (EnviE)	Monitor Temperature / Humidity at DUT level	<u>Environemental</u> <u>Monitoring Expander -</u> <u>EnviE</u>
	Front-End readout board	12 GHz fast transimpedance amplifier with integrated faraday cage	Single Channel Board
Mechanics	Cold-Box and DUT Support	XPS foam enclosure for -20C operation and individual DUT alignment	Test beam Mechanics
Software	Oscilloscope Fast DAQ	SCPI layer DAQ program for oscilloscope readout	Oscilloscope DAQ
	Power/ Temp Control Software	Labview based Low Voltage and HV control software with integrated single event burnout protection	<u>TiCAS - Timing Control</u> <u>Automation Software</u>
	Trimming analysis Software	LGADUtils timing analysis framework	LGADUtils

•Single Event Burn-out

Single Event Burn-Out was also observed in 3D sensors but in much Higher fields than LGADs (~ 30 V / μ m) but 1e16 (not 1e17)

BUT



3D Single Pixel structures

Coomotru	Irradiation		Operating Conditions	
Geometry	Species	Flu. (n _{eq} /cm²)	Operating Conditions	
	Unirradiated		-50 V	1.4 V/μm
		1 × 10 ¹⁵	-180 V	5.1 V/μm
CNM 13680-6	Fast Neutrons	8 × 10 ¹⁵	-310 V	8.7 V/μm
Single 3D	@ JSI	6 × 10 ¹⁶	-360 V	10.1 V/μm
25 x 100		1 × 10 ¹⁷	-410 V	11.5 V/μm
	PS protons	1 × 10 ¹⁵	-210 V	5.9 V/μm
	(24 GeV/c)	8 × 10 ¹⁵	-180 V	5.1 V/μm
	Unirradiated		60 V	3.2 V/µm
CNM 5936-11		1 × 10 ¹⁵	-160 V	8.5 V/μm
Double 3D	Fast Neutrons	8 × 10 ¹⁵	-170 V	9.0 V/μm
55 x 55	@ JSI	6 × 10 ¹⁶	-120 V	6.3 V/μm
		1 × 10 ¹⁷	-200 V	10.6 V/μm
	Unirradiated			2.6 V/μm
CNM 13680-6	Fast Neutrons	1 × 10 ¹⁵	-200 V	10.3 V/μm
Single 3D		6 × 10 ¹⁶	-320 V	16.5 V/μm
50 x 50	@ JSI	1 × 10 ¹⁷	-340 V	17.6 V/μm
	PS protons	1 × 10 ¹⁵	-180 V	9.3 V/μm